Special Issue

Deep Learning for Image Recognition and Processing

Message from the Guest Editors

Deep learning technology has been drawing increasing interest for a wide range of computer vision and image analysis tasks, such as image classification, image segmentation, object detection and so on. A number of applications can be utilized by deep learning technology, such as industrial intelligence, remote sensing image analysis and autonomous driving. However, deep learning technology has faced some challenging problems in various applications, limiting image recognition and processing performance. Some modified deep learning on model-based or module-based strategies cannot cope with the volume of problems, and this must be urgently addressed: for example, how to improve deep learning model accuracy by using a limited sample size, or how to propose an explainable deep learning model to make it precise and reliable. As a result, this Special Issue aims to cover novel strategies on deep learning algorithms for image recognition and processing by using reliable, optimized and hybrid deep learning algorithms in a number of applications.

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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